



AON4604

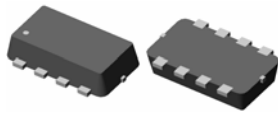
Complementary Enhancement Mode Field Effect Transistor

General Description

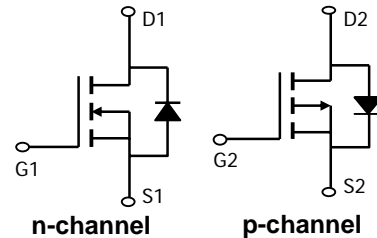
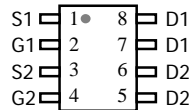
The AON4604 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications. *Standard Product AON4604 is Pb-free (meets ROHS & Sony 259 specifications).*

Features

	n-channel	p-channel
V_{DS} (V) =	20V	-20V
I_D =	5.4A	-3.8A ($V_{GS} = \pm 4.5V$)
$R_{DS(ON)} <$	42m Ω	< 90m Ω ($V_{GS} = \pm 4.5V$)
$R_{DS(ON)} <$	52m Ω	< 120m Ω ($V_{GS} = \pm 2.5V$)
$R_{DS(ON)} <$	72m Ω	< 170m Ω ($V_{GS} = \pm 1.8V$)



DFN3X2-8L



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	20	-20	V
Gate-Source Voltage	V_{GS}	± 8	± 8	V
Continuous Drain Current ^A	$T_A=25^\circ\text{C}$	5.4	-3.8	A
		$T_A=70^\circ\text{C}$	4.3	
Pulsed Drain Current ^B	I_{DM}	15	-15	
Power Dissipation	$T_A=25^\circ\text{C}$	1.9	1.9	W
		$T_A=70^\circ\text{C}$	1.2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	$^\circ\text{C}$

Thermal Characteristics: n-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	51.5	65	$^\circ\text{C/W}$
$t \leq 10\text{s}$				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	82	100	$^\circ\text{C/W}$
Steady-State				
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	37	50	$^\circ\text{C/W}$

Thermal Characteristics: p-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	51.5	65	$^\circ\text{C/W}$
$t \leq 10\text{s}$				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	82	100	$^\circ\text{C/W}$
Steady-State				
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	37	50	$^\circ\text{C/W}$

n-channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	0.4	0.7	1	V
$I_{D(ON)}$	On state drain current	$V_{GS}=4.5\text{V}$, $V_{DS}=5\text{V}$	15			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}$, $I_D=5.4\text{A}$ $T_J=125^\circ\text{C}$		34 50	42 70	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}$, $I_D=4.8\text{A}$		43	52	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}$, $I_D=4\text{A}$		57	72	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=5.4\text{A}$		11		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}$, $V_{GS}=0\text{V}$		0.8	1	V
I_S	Maximum Body-Diode Continuous Current				2.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=10\text{V}$, $f=1\text{MHz}$		436		pF
C_{oss}	Output Capacitance			66		pF
C_{riss}	Reverse Transfer Capacitance			44		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		3		Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}$, $V_{DS}=10\text{V}$, $I_D=5.4\text{A}$		6.5		nC
Q_{gs}	Gate Source Charge			0.8		nC
Q_{gd}	Gate Drain Charge			2.1		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=5\text{V}$, $V_{DS}=10\text{V}$, $R_L=1.9\Omega$, $R_{GEN}=6\Omega$		7		ns
t_r	Turn-On Rise Time			11.2		ns
$t_{D(off)}$	Turn-Off Delay Time			36.5		ns
t_f	Turn-Off Fall Time			12.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=5.4\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		15.2		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=5.4\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		4.7		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

The SOA curve provides a single pulse rating.

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TYPICAL N-CANNEL ELECTRICAL AND THERMAL CHARACTERISTICS

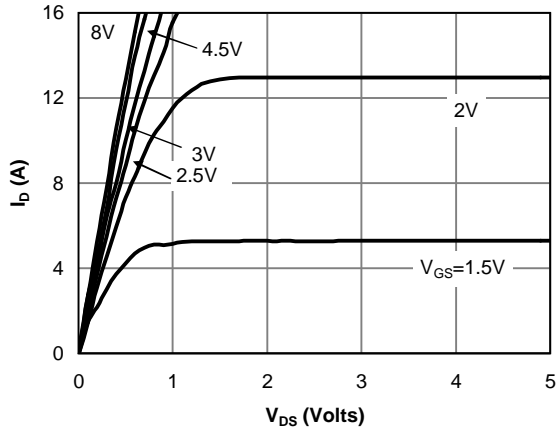


Figure 1: On-Region Characteristics

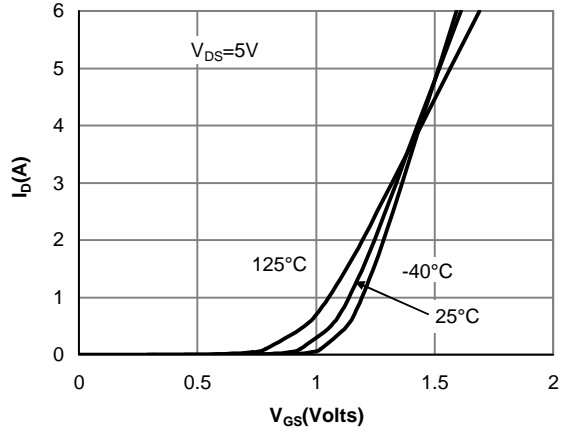


Figure 2: Transfer Characteristics

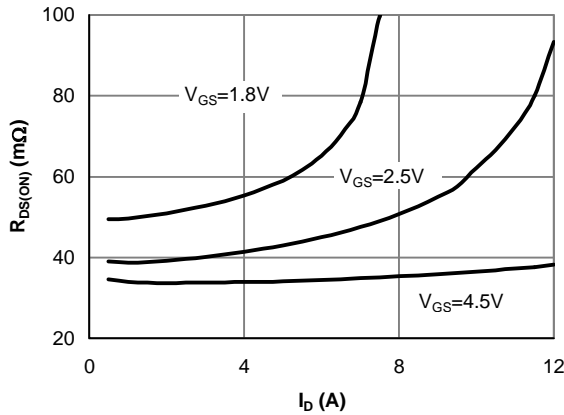


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

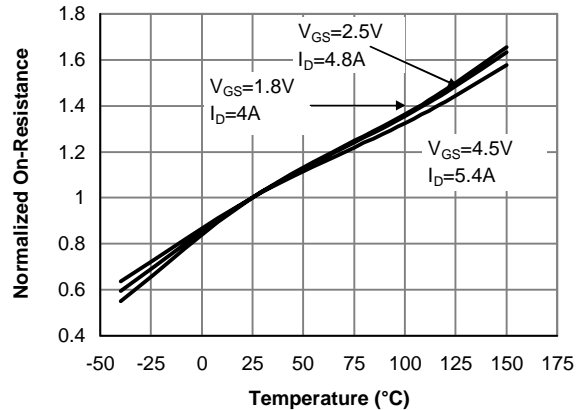


Figure 4: On-Resistance vs. Junction Temperature

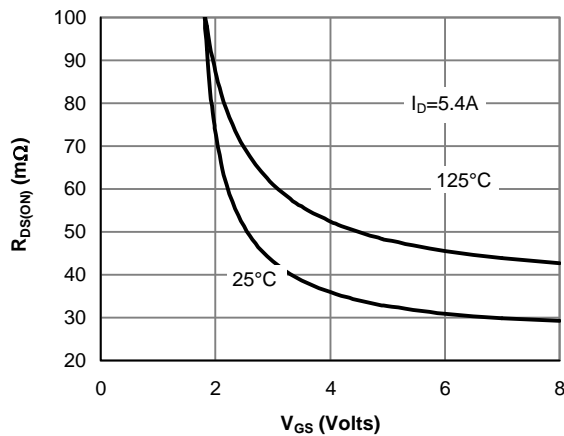


Figure 5: On-Resistance vs. Gate-Source Voltage

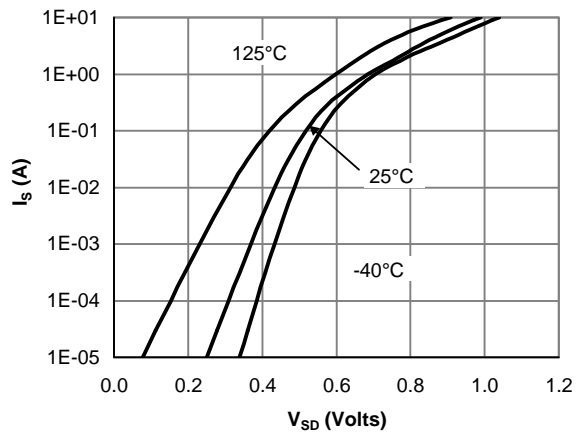


Figure 6: Body-Diode Characteristics

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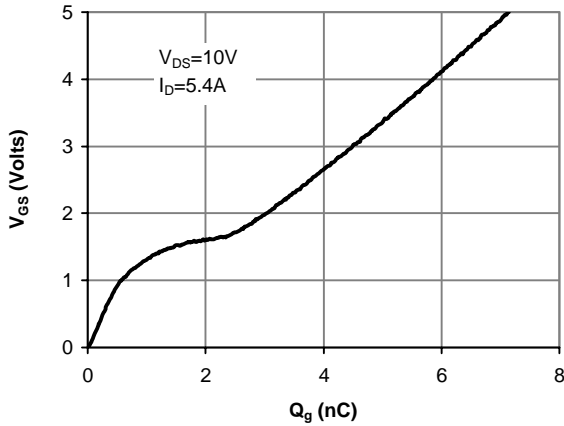


Figure 7: Gate-Charge Characteristics

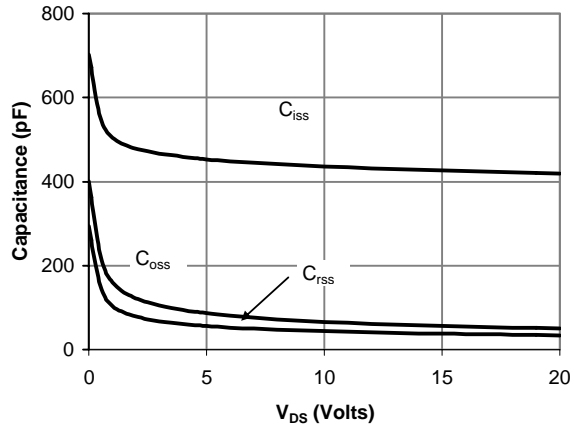


Figure 8: Capacitance Characteristics

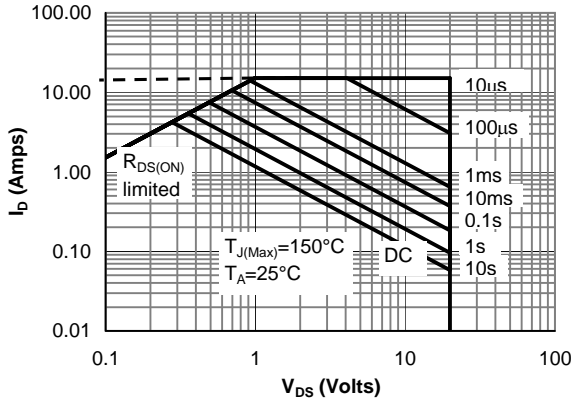


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

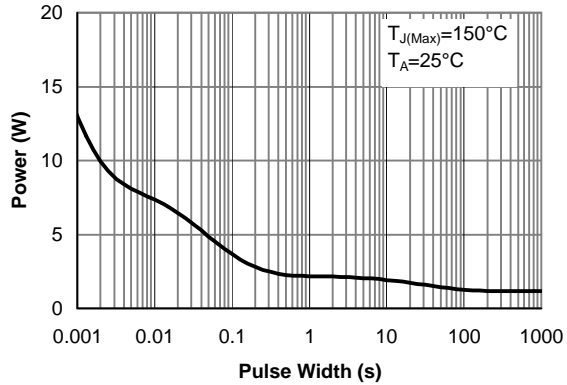


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

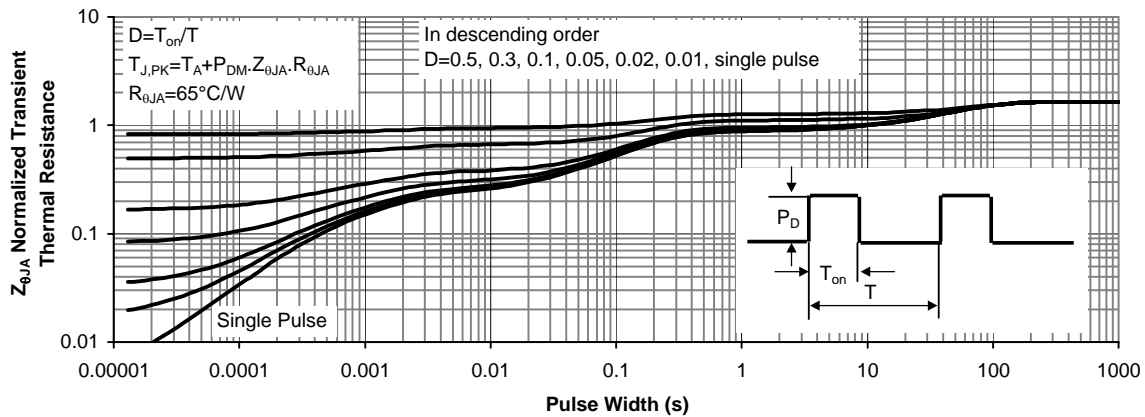


Figure 11: Normalized Maximum Transient Thermal Impedance

p-channel MOSFET Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, V _{GS} =0V	-20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-16V, V _{GS} =0V T _J =55°C			-1 -5	μA
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±8V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} I _D =-250μA	-0.3	-0.63	-1	V
I _{D(ON)}	On state drain current	V _{GS} =-4.5V, V _{DS} =-5V	-15			A
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-4.5V, I _D =-3.8A T _J =125°C		73	90	mΩ
		V _{GS} =-2.5V, I _D =-3.3A		95	120	
		V _{GS} =-1.8V, I _D =-2.8A		130	170	mΩ
g _{FS}	Forward Transconductance	V _{DS} =-5V, I _D =-3.8A		7		S
V _{SD}	Diode Forward Voltage	I _S =-1A, V _{GS} =0V		-0.83	-1	V
I _S	Maximum Body-Diode Continuous Current				-2.5	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-10V, f=1MHz		540		pF
C _{oss}	Output Capacitance			72		pF
C _{rss}	Reverse Transfer Capacitance			49		pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		12	18	Ω
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{GS} =-4.5V, V _{DS} =-10V, I _D =-3.8A		5.9		nC
Q _{gs}	Gate Source Charge			0.9		nC
Q _{gd}	Gate Drain Charge			1.9		nC
t _{D(on)}	Turn-On Delay Time	V _{GS} =-4.5V, V _{DS} =-10V, R _L =2.6Ω, R _{GEN} =3Ω		11.5		ns
t _r	Turn-On Rise Time			15.5		ns
t _{D(off)}	Turn-Off Delay Time			37.5		ns
t _f	Turn-Off Fall Time			23		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =-3.8A, dI/dt=100A/μs		23.1		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =-3.8A, dI/dt=100A/μs		8.9		nC

A: The value of R_{θJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

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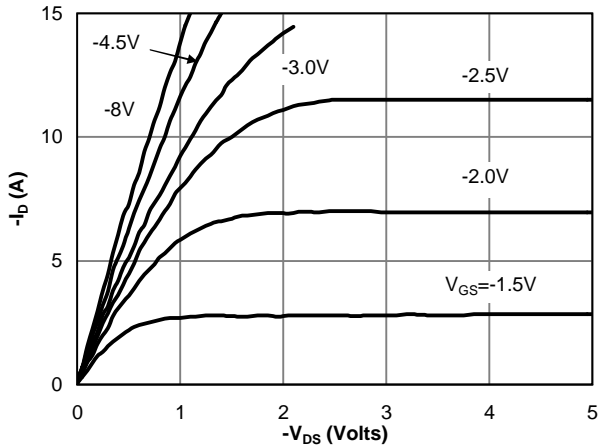


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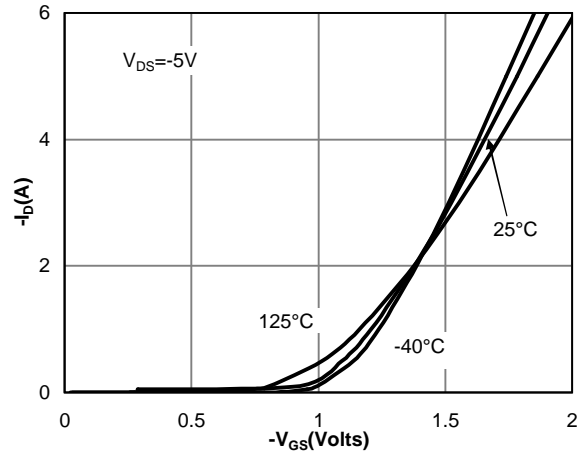


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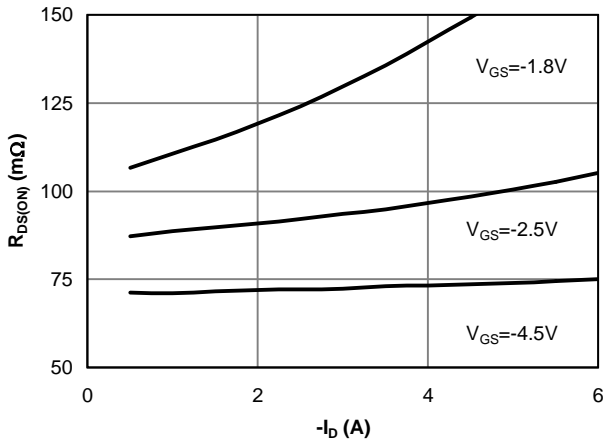


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

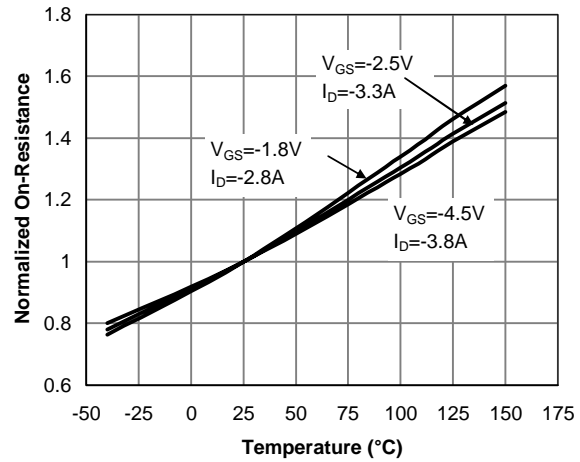


Figure 4: On-Resistance vs. Junction Temperature

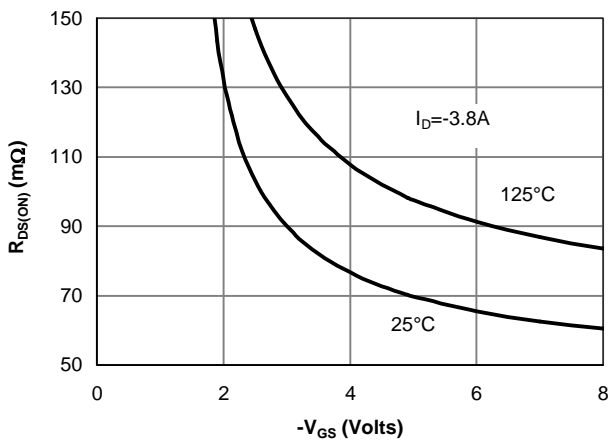


Figure 5: On-Resistance vs. Gate-Source Voltage

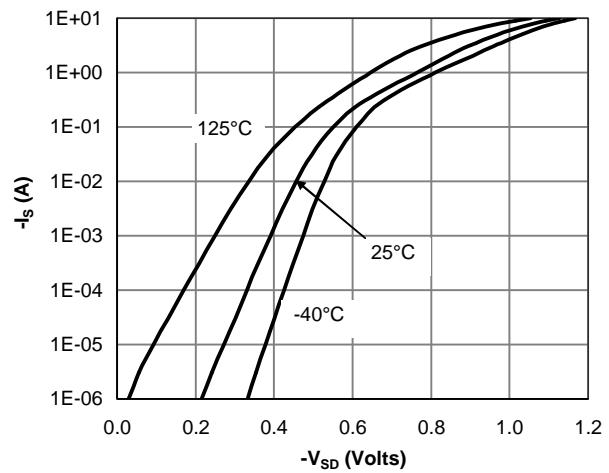


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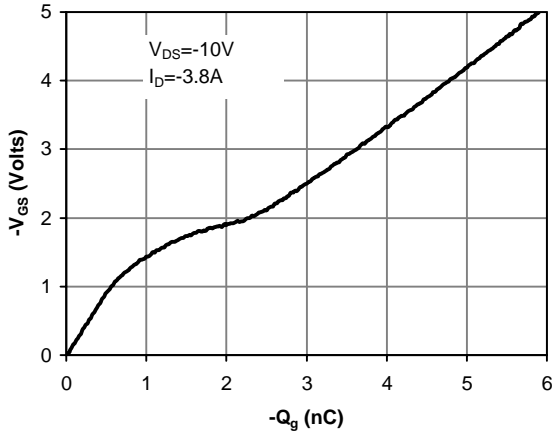


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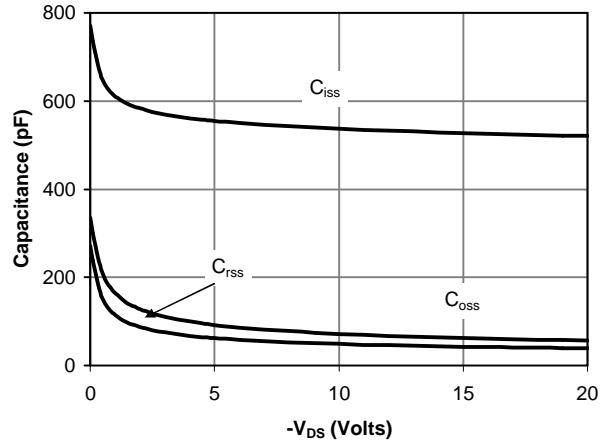


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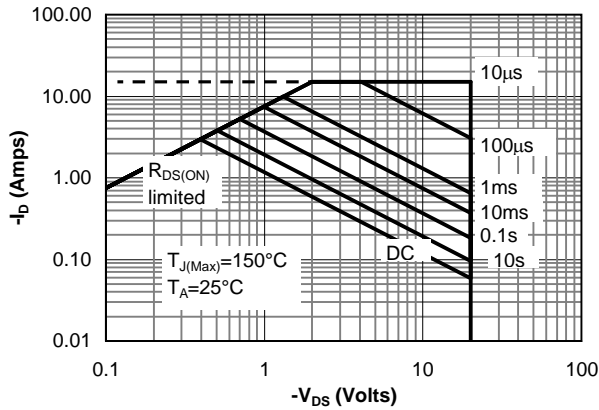


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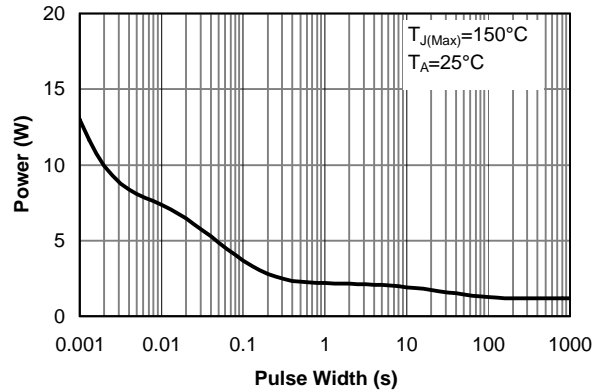


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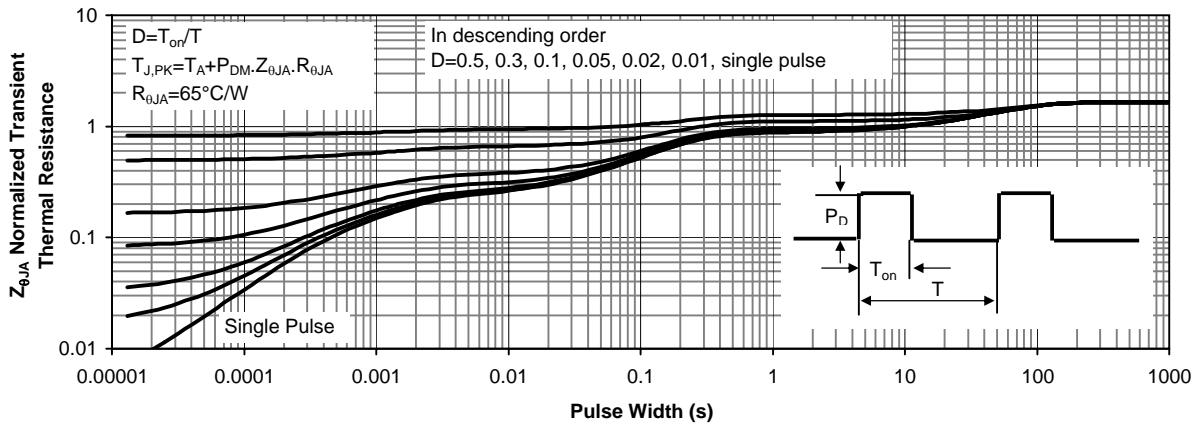


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